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Inf rmation Disc! sure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant James J. Estrada		
		Filing Date	Group Art Unit 2128	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Examiner Signature	/Brandon Hsieh/	Date Considered	03/23/2007
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